DATA SHEET

MOS FIELD EFFECT TRANSISTOR

NP86N04EHE, NP86N04KHE NP86N04CHE, NP86N04DHE, NP86N04MHE, NP86N04NHE

SWITCHING N-CHANNEL POWER MOS FET

DESCRIPTION

These products are N-channel MOS Field Effect Transistors designed for high current switching applications.

ORDERING INFORMATION

PART NUMBER	LEAD PLATING	PACKING	PACKAGE	
NP86N04EHE-E1-AY Note1, 2			TO 2022 (MD 2571) by 4.4 s	
NP86N04EHE-E2-AY Note1, 2	Dura Ca (Tia)	Tono 200 n/rool	TO-263 (MP-25ZJ) typ. 1.4 g	
NP86N04KHE-E1-AY Note1	Pure Sn (Tin)	Tape 800 p/reel	TO-263 (MP-25ZK) typ. 1.5 g	
NP86N04KHE-E2-AY Note1		A32 7.4		
NP86N04CHE-S12-AZ Note1, 2	Sn-Ag-Cu		TO-220 (MP-25) typ. 1.9 g	
NP86N04DHE-S12-AY Note1, 2	- TP- CO	Tuba FO altuba	TO-262 (MP-25 Fin Cut) typ. 1.8 g	
NP86N04MHE-S18-AY Note1	Pure Sn (Tin)	Tube 50 p/tube	TO-220 (MP-25K) typ. 1.9 g	
NP86N04NHE-S18-AY Note1			TO-262 (MP-25SK) typ. 1.8 g	

Notes 1. Pb-free (This product does not contain Pb in the external electrode.)

2. Not for new design

FEATURES

- Channel temperature 175 degree rated
- Super low on-state resistance

 $R_{DS(on)}$ = 4.4 m Ω MAX. (Vgs = 10 V, ID = 43 A)

• Low input capacitance

Ciss = 5900 pF TYP.

Built-in gate protection diode





(TO-262)



(TO-263)



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ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

Drain to Source Voltage (Vgs = 0 V)	VDSS	40	V
Gate to Source Voltage (VDS = 0 V)	Vgss	±20	V
Drain Current (DC) (Tc = 25°C) Note1	ID(DC)	±86	Α
Drain Current (Pulse) Note2	ID(pulse)	±344	Α
Total Power Dissipation (Tc = 25°C)	PT	230	W
Total Power Dissipation (T _A = 25°C)	PT	1.8	W
Channel Temperature	Tch	175	°C
Storage Temperature	T _{stg}	-55 to +175	°C
Single Avalanche Current Note3	las	86/67/24	Α
Single Avalanche Energy Note3	Eas	74/450/580	mJ

Notes 1. Calculated constant current according to MAX. allowable channel temperature.

- **2.** PW \leq 10 μ s, Duty cycle \leq 1%
- 3. Starting T_{ch} = 25°C, V_{DD} = 20 V, R_G = 25 Ω , V_{GS} = 20 \rightarrow 0 V (see Figure 4.)

THERMAL RESISTANCE

Channel to Case Thermal Resistance	Rth(ch-C)	0.65	°C/W
Channel to Ambient Thermal Resistance	Rth(ch-A)	83.3	°C/W

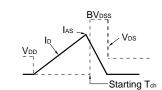
NEC

ELECTRICAL CHARACTERISTICS (TA = 25°C)

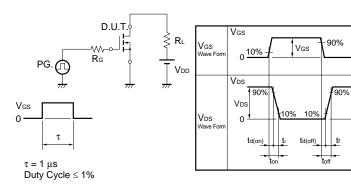
CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	Ipss	V _{DS} = 40 V, V _{GS} = 0 V			10	μА
Gate Leakage Current	Igss	V _{GS} = ±20 V, V _{DS} = 0 V			±10	μА
Gate to Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	2.0	3.0	4.0	V
Forward Transfer Admittance	yfs	V _{DS} = 10 V, I _D = 43 A	29	57		S
Drain to Source On-state Resistance	R _{DS(on)}	V _{GS} = 10 V, I _D = 43 A		3.5	4.4	mΩ
Input Capacitance	Ciss	V _{DS} = 25 V,		5900	8900	pF
Output Capacitance	Coss	V _{GS} = 0 V,		1200	1800	pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		530	960	pF
Turn-on Delay Time	t _{d(on)}	$V_{DD} = 20 \text{ V}, I_D = 43 \text{ A},$		32	71	ns
Rise Time	tr	V _{GS} = 10 V,		24	59	ns
Turn-off Delay Time	t _{d(off)}	R _G = 1 Ω		110	220	ns
Fall Time	tr			33	82	ns
Total Gate Charge	QG	V _{DD} = 32 V,		110	170	nC
Gate to Source Charge	Q _G s	V _{GS} = 10 V,		22		nC
Gate to Drain Charge	Q _{GD}	I _D = 86 A		36		nC
Body Diode Forward Voltage	V _{F(S-D)}	I _F = 86 A, V _{GS} = 0 V		0.93		V
Reverse Recovery Time	trr	I _F = 86 A, V _{GS} = 0 V,		70		ns
Reverse Recovery Charge	Qrr	di/dt = 100 A/μs		125		nC

TEST CIRCUIT 1 AVALANCHE CAPABILITY

$\begin{array}{c} \text{D.U.T.} \\ \text{Rg} = 25 \, \Omega \\ \text{VGS} = 20 \rightarrow 0 \, \text{V} \\ \end{array} \begin{array}{c} \text{PG.} \\ \text{$\stackrel{>}{>}$} 50 \, \Omega \\ \text{$\stackrel{>}{>}$} \end{array} \begin{array}{c} \text{Vob} \\ \text{$\stackrel{>}{>}$} \end{array}$



TEST CIRCUIT 2 SWITCHING TIME



TEST CIRCUIT 3 GATE CHARGE

$$\begin{array}{c|c}
D.U.T. & \\
l_{G} = 2 \text{ mA} & \\
\hline
PG. & \\
\end{array}$$

$$\begin{array}{c|c}
S & \Omega & \\
\end{array}$$

$$\begin{array}{c|c}
V_{DD} & \\
\end{array}$$

20

0 **L**

25

TYPICAL CHARACTERISTICS (TA = 25°C)

Figure 1. DERATING FACTOR OF FORWARD BIAS SAFE OPERATING AREA % dT - Percentage of Rated Power -100 80 60 40

50 75 100 125 150 175 200 Tc - Case Temperature - °C

Figure 2. TOTAL POWER DISSIPATION vs. CASE TEMPERATURE 280 Power Dissipation - W 240 200 160 120 P_T - Total 80 40 0 25 0 75 100 125 150 175 200 Tc - Case Temperature - °C

Figure 3. FORWARD BIAS SAFE OPERATING AREA

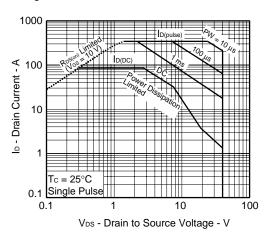


Figure4. SINGLE AVALANCHE ENERGY DERATING FACTOR

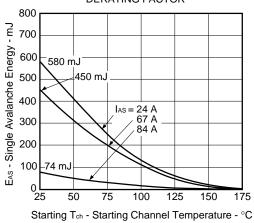
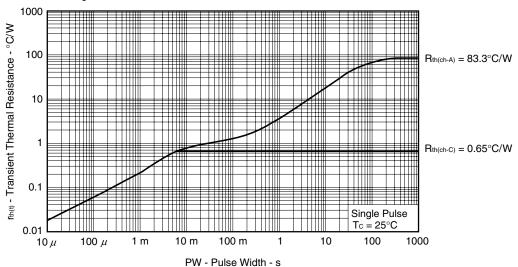


Figure 5. TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH



4

Figure 6. FORWARD TRANSFER CHARACTERISTICS

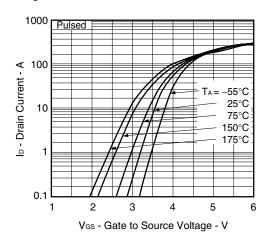


Figure 7. DRAIN CURRENT vs.
DRAIN TO SOURCE VOLTAGE Pulsed

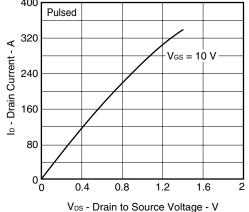


Figure8. FORWARD TRANSFER ADMITTANCE vs. DRAIN CURRENT

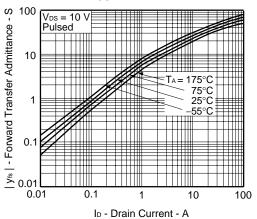


Figure9. DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE

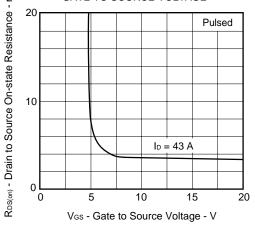
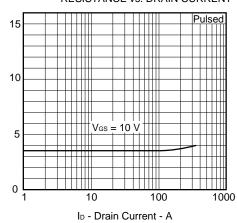
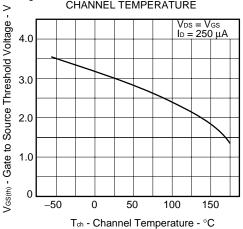


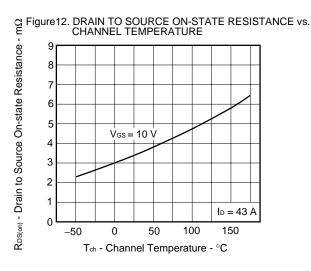
Figure 10. DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT

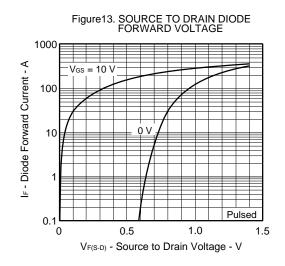


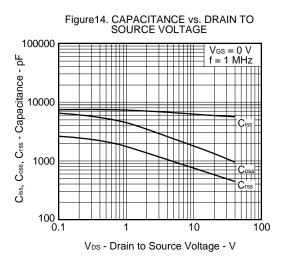
R_{DS(on)} - Drain to Source On-state Resistance - mΩ

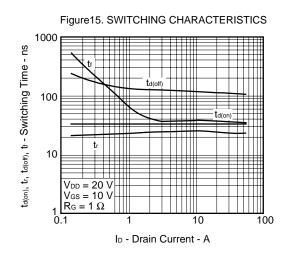
Figure 11. GATE TO SOURCE THRESHOLD VOLTAGE vs. CHANNEL TEMPERATURE

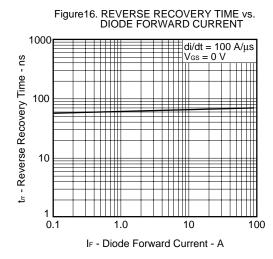












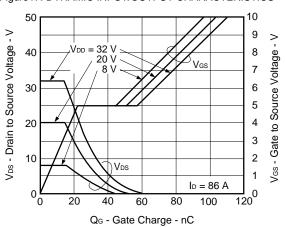
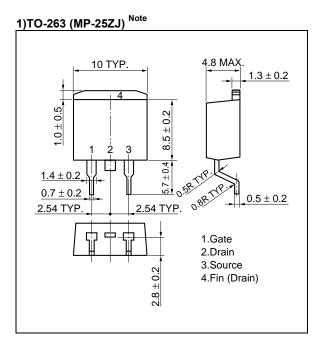
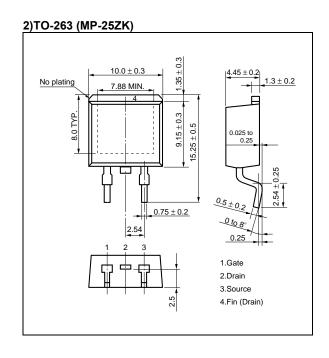
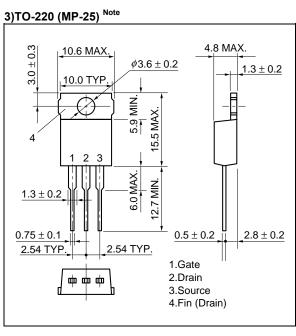


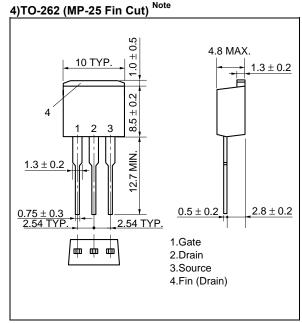
Figure 17. DYNAMIC INPUT/OUTPUT CHARACTERISTICS

<R> PACKAGE DRAWINGS (Unit: mm)

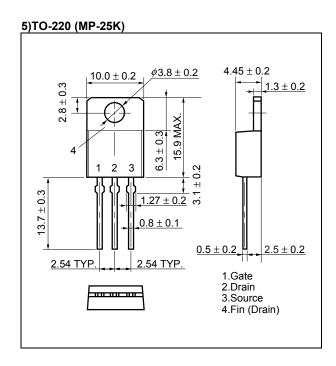


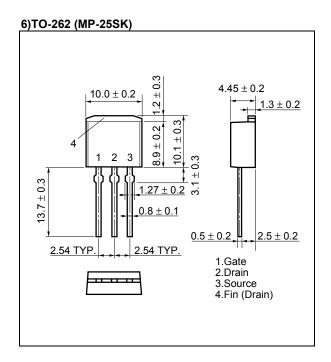




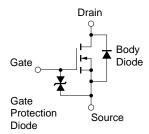


Note Not for new design





EQUIVALENT CIRCUIT

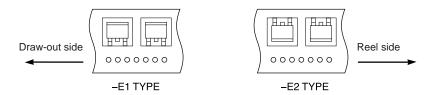


Remark The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

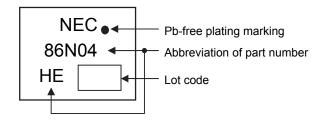


<R> TAPE INFORMATION

There are two types (-E1, -E2) of taping depending on the direction of the device.



<R> MARKING INFORMATION



<R> RECOMMENDED SOLDERING CONDITIONS

These products should be soldered and mounted under the following recommended conditions.

For soldering methods and conditions other than those recommended below, please contact an NEC Electronics sales representative.

For technical information, see the following website.

Semiconductor Device Mount Manual (http://www.necel.com/pkg/en/mount/index.html)

Soldering Method	Soldering Conditions	Recommended Condition Symbol	
Infrared reflow	Maximum temperature (Package's surface temperature): 260°C or below		
MP-25ZJ, MP-25ZK	Time at maximum temperature: 10 seconds or less		
	Time of temperature higher than 220°C: 60 seconds or less	IR60-00-3	
	Preheating time at 160 to 180°C: 60 to 120 seconds		
	Maximum number of reflow processes: 3 times		
	Maximum chlorine content of rosin flux (percentage mass): 0.2% or less		
Wave soldering	Maximum temperature (Solder temperature): 260°C or below		
MP-25, MP-25K, MP-25SK,	Time: 10 seconds or less	THDWS	
MP-25 Fin Cut	Maximum chlorine content of rosin flux: 0.2% (wt.) or less		
Partial heating	Maximum temperature (Pin temperature): 350°C or below		
MP-25ZJ, MP-25ZK,	Time (per side of the device): 3 seconds or less	P350	
MP-25K, MP-25SK	Maximum chlorine content of rosin flux: 0.2% (wt.) or less		
Partial heating	Maximum temperature (Pin temperature): 300°C or below		
MP-25, MP-25 Fin Cut	Time (per side of the device): 3 seconds or less	P300	
	Maximum chlorine content of rosin flux: 0.2% (wt.) or less		

Caution Do not use different soldering methods together (except for partial heating).

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